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ASSEMBLY

# Reduction of silver usage in ECA based interconnection

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### **Challenges of TW scale PV manufacturing**



Solar Power Europe, Global PV market Forecast, 2022, B. Hallam et al. 2022

Abundance of elements in the Earth's upper crust (G. Haxel 2018)

- Silver availability is one of the most alarming concerns for the expansion of the PV industry at the TWp scale
- Currently the PV industry is using more than 15 % globally available Ag
- Current projection indicate that latest cell technologies of TOPCON and SHJ technologies would require the entire supply of Ag -> Ag reduction is a must !



#### **Gluing with ECAs for HJT and TANDEMS**

#### Electrically Conductive Adhesive (ECA)

- Conductive particles (approx 40-70 w% Ag)
- Epoxy or Acrylate Matrix



- Reliability proven process
- Lead and Bismuth free
- Low T process < 200°C
- Copper based ECA available now



- ECA Mondragon TABBER STRINGER
  - Multi-ribbon handling up to 20 wires & ribbons
  - G12 cells compatible @ INES
  - Thin cell handling down to 110 µm
  - Independent printing of the 2 cell sides
  - Provide developed curing profiles
  - Gapless and Paving compatible







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Finding a balance between critical material usage and performance, while maintaining reliability



#### **Experimental workflow**

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#### **INITIAL Performances (T0)**

FF according to the Amount of

deposited ECA



- Busbar cell: Initial performance independent of the amount of ECA
- Busbarless configuration: Initial performance is closely related to the amount of ECA
- Good initial performances around 27 mg/Wp Ag total consumption

FF according to the total Ag weight /Wp

(Total Ag : ECA + Ribbon + Cells)

37.0

#### Fill Factor losses after 600 TC

FF loss according to the amount

FF loss according to the total Ag weight /Wp

of deposited ECA







- Decrease of power mainly due to FF
- In the both configurations, the FF losses are closely related to the amount of deposited ECA
- Same tendencies as after 200 & 400 TC
- Less than 2.5 % degradation after 600 TC with 27 mgAg/W in the module

#### **EL characterization : Busbarless Cells**



- EL degradation on the borders after 600 TC and depends on the amount of deposited ECA
- Higher degradation observed than on Busbar Cells
- No Isc and Voc degradation after TC (1 SUN I-V)

-> FF degradation is linked to an increase of the series resistance on BB0 and Busbar Cells



## Low Ag content ECA and Ag/Cu Cell Metallization

- FF loss in function of Ag weight /Wp
  (Total Ag : ECA + Ribbon + Cells)
- 1 Busbar configuration

- ECAs with reduced Silver content (< 40 %) show impressive results : 2 % FF loss after 600 TC
- Silver-Copper metallized cells allows to reach a low total
  Ag consumption close to 25 mg/Wp with a degradation of
  2 % after 600 TC







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#### **Conclusion of the study**

- Reliability of ECA gluing interconnection (in TC) in both busbarless and busbar cell configurations is closely related to the amount of deposited ECA
- Ag content in ECA can be lowered with no impact
- AgCu cell metallization allows to reach a low total Ag consumption close to 25 mg/W on modules with a degradation of 2 % after 600 TC
- On BB0 cells (-5mg/W), a consumption of 16 mg/Wp should be reachable in short term on HJT modules by coupling Ag/Cu metallization and low Ag content ECA



#### **Strategies for further Ag reduction**

- Improved deposition accuracy (< 100 µm)</li>
- Ribbons with Ag-free coating
- Wire gluing
- Novel Cu-particle based ECAs
- Perovskite devices interconnection

Radical reduction of Ag metallization is a must for TW scale manufacturing in PV We must target 5-10 mg/Wp by 2030





# Thank you for your attention

